PCN Number:	201500	20000			DCN	Date:	10/19/2015
					FCI	Date.	10/19/2013
Title: DLPC343X Rev C Yield Enhancement Redesign							
Customer Contact: Dlp_pcn_tea		pcn_tean	<u>n@list.ti.com</u>	Dept:		DLP® CQE	
Proposed 1 st Ship Date:		DLPC3430 10/01/2016 DLPC3433 04/01/2016 DLPC3435 10/01/2016 DLPC3438 04/01/2016 DLPC3439 04/01/2016		Estimated Sample Availability:		DLPC34 DLPC34 DLPC34	30 10/13/2015 33 12/01/2015 35 12/01/2015 38 10/13/2015 39 12/01/2015
Change Type:							
Assembly Site		Design		Wafer Bump Site			
Assembly Process		Data Sheet		Wa	Wafer Bump Material		
Assembly Materials		Part number change		Wa	Wafer Bump Process		
Mechanical Specification		Test Site			afer Fab		
Packing/Shipping/Labeling			Test Process		Wa	Wafer Fab Materials	
			Wafer Fab Process				
PCN Details							
Description of Change:							
IC supplier of DLPC343X found one flip-flop cell to adversely affected yield but not device							

functionality. The flip-flop cell type was changed to improve manufacturing throughput.

Reason for Change:

Yield Improvement

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

There is no anticipated impact to fit, function, quality or reliability. There is a form change which includes part number marking and orderable part number change as described below.

Changes to product identification resulting from this PCN:

The part number marking and orderable part number are changing to Rev C as shown below,

From (Rev B)	To (Rev C)			
DLPC3430ZVBR	DLPC3430CZVBR			
2512737-0002R 2512737-0102R	DLPC3431CZVBR			
DLPC3433ZVB				
2512737-0032	DLPC3433CZVB			
DLPC3435ZEZ	DLPC3435CZEZ			
2512737-0052				
DLPC3438ZEZ	DLPC3438CZFZ			
2512737-0082	DEI CO IOCCEE			
DLPC3439ZEZ	DLPC3439CZEZ			
2512737-0092				

Product Affected:

2512737-0002R, 2512737-0032, 2512737-0052, 2512737-0082, 2512737-0092, 2512737-0102R, DLPC3430ZVBR, DLPC3433ZVB, DLPC3435ZEZ, DLPC3438ZEZ, DLPC3439ZEZ

Qualification Data This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications. **Qual Vehicle: Device Vehicle** Qualification: ☐ Plan ☐ Test Results Conditions Test Results Per data sheet Pass **Electrical Characterization** QBS* Reliability Tests System Validation Tests Pass Environmental & Bench Level Software tests Note: *QBS (Qual by Similarity) to Rev A

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail				
DLP® Products	Dlp-pcn-team@list.ti.com				
USA	PCNAmericasContact@list.ti.com				
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